

Abstract Submitted
for the SES06 Meeting of
The American Physical Society

EXAFS investigation of the amorphous $\text{Ge}_2\text{Sb}_2\text{Te}_5$ optical memory material JOSEPH WASHINGTON, DAVID BAKER, GERALD LUCOVSKY, MICHAEL PAESLER, North Carolina State University, CRAIG TAYLOR, Colorado School of Mines — Studies of amorphous (a-) semiconductors have been driven by technological advances as well as fundamental theories. Observation of electrical switching, for example, fueled early interest in a-chalcogenides. More recently a-chalcogenide switching has been applied successfully to programmable memory devices, as well as DVD technology where the quest for the discovery of better-suited materials continues. Thus, switching grants researchers today with an active arena of technological as well as fundamental study. Bond constraint theory and rigidity theory provide a powerful framework for understanding the structure and properties of a-materials. Application of these theories to switching in a-chalcogenides, combined with Extended X-ray Absorption Fine Structure (EXAFS) spectroscopy yields the most detailed model to date of the a- $\text{Ge}_2\text{Sb}_2\text{Te}_5$ system.

David Baker
North Carolina State University

Date submitted: 21 Aug 2006

Electronic form version 1.4